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TRANSMITTAL FORM

(to be used for all correspondence after initial filing)

Application Number	09/759,414
Filing Date	01-13-2001
First Named Inventor	LI, ZHE
Group Art Unit	2123
Examiner Name	TESKA, KEVIN J
Total Number of Pages in This Submission	
Attorney Docket Number	

ENCLOSURES *(check all that apply)*

- ☐ Fee Transmittal Form
  - ☐ Fee Attached
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- ☐ Assignment Papers *(for an Application)*
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- ☐ Proprietary Information
- ☐ Status Letter
- ☐ Other Enclosure(s) *(please identify below)*:

Remarks

SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT

Firm *or* Individual name	Zhe Li
Signature	Zhe Li
Date	04-18-2002

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 1 of 2

Complete if Known	
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OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[2]
		S.-Y. HUANG et al, "AutoFix: a hybrid tool for automatic logic rectification" IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol. 18, no. 9, September 1999, pp. 1376-1384, IEEE, U.S.A.	
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		D. BRAND et al, "Incremental synthesis" Proceedings International Conference on Computer-Aided Design, November 1994, pp. 14-18, ACM, U.S.A.	

Examiner Signature		Date Considered	

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 2 of 2

Complete if Known	
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		A. KUEHLMANN et al, "Error diagnosis for transistor-level verification" Proceedings Design Automation Conference, June 1994, pp. 218-224, ACM, U.S.A.	
		I. POMERANZ and S.M. REDDY, "A method for diagnosing implementations errors in synchronous sequential circuits and its implications on synthesis" Proceedings European Conference on Design Automation, September 1993, pp. 252-258, IEEE.	
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		K.A. TAMURA, "Locating functional errors in logic circuits" Proceedings Design Automation Conference, June 1989, pp. 185-191, ACM, U.S.A.	

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